1	ABSTRACT OF THE DISCLOSURE
2	The present invention relates to a memory interlace-checking method and, in
3	particular, to a test method that can effectively detect the weakening of memory.
4	This test method is different from the eonventional continuous address testing style.
5	It is an interlacing address test method that comprises a main step and a data
6	checking step. The main step provides main data to perform command actions on
.7	local addresses in memory. This will weaken other portions in the memory that are
8	not trigged by commands because of the electromagnetic interference (EMI)
9	induced by memory operations. Afterwards, in the data checking step, the yet to be
10	triggered portion will be checked in a complementary way in order to accurately
11	detect weakened memory.